



P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)		
- 30	0.045 at V _{GS} = - 10 V	- 5.9	7 nC		
	0.075 at V _{GS} = - 4.5 V	- 4.6	7110		

TO-236 (SOT-23) G 1 Top View Si2343CDS (P1)* * Marking Code

Ordering Information: Si2343CDS-T1-GE3 (Lead (Pb)-free and Halogen-free)

FEATURES

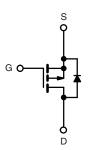
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC



ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Load Switch
- Notebook Adaptor Switch
- DC/DC Converter



P-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 30	V	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		- 5.9		
Continuous Dusin Commant (T., 150 °C)	T _C = 70 °C		- 4.7		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	l _D	- 4.2 ^{b, c}		
	T _A = 70 °C		- 3.3 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	- 25		
Continous Source-Drain Diode Current	T _C = 25 °C		- 2.1		
	T _A = 25 °C	- I _S	- 1 ^{b, c}		
Maximum Power Dissipation	T _C = 25 °C		2.5		
	T _C = 70 °C		1.6	147	
	T _A = 25 °C	P _D	1.25 ^{b, c}	w	
	T _A = 70 °C		0.8 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	75	100	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	40	50		

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 5 s
- d. Maximum under Steady State conditions is 166 $^{\circ}\text{C/W}.$
- e. Package Limited.

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SPECIFICATIONS $T_J = 25 ^{\circ}C$, Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	Cymbol	rest conditions		1,75.	WIUX.	Oint
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 19		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.4		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = -250 \mu A$	- 1.2		- 2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V			- 1	μΑ
		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 25			Α
Drain-Source On-State Resistance ^a	. ,	V _{GS} = - 10 V, I _D = - 4.2 A		0.037	0.045	Ω
	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 3.2 A		0.062	0.075	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 4.2 A		10		S
Dynamic ^b				•	•	
Input Capacitance	C _{iss}			590		pF
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		115		
Reverse Transfer Capacitance	C _{rss}	1		93		
Total Gata Chargo	Q _g	V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 4.2 A		13.6	21	nC
Total Gate Charge				7	11	
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -4.2 \text{ A}$		2.3		
Gate-Drain Charge	Q_{gd}			3.2		
Gate Resistance	R_g	f = 1 MHz	1	5	10	Ω
Turn-On Delay Time	t _{d(on)}			30	45	ns
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 4.5 \Omega$		25	38	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -3.3 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		16	24	
Fall Time	t _f			8	16	
Turn-On Delay Time	t _{d(on)}			8	16	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 4.5 Ω		10	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 3.3 A, V_{GEN} = - 10 V, R_g = 1 Ω		18	27	
Fall Time	t _f]		8	16	
Drain-Source Body Diode Characteristi	cs			•	•	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.2	A
Pulse Diode Forward Current	I _{SM}				- 25	^
Body Diode Voltage	V_{SD}	I _S = - 3.3 A, V _{GS} = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			17	26	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 3.3 A, dl/dt = 100 A/μs, T _J = 25 °C		9	18	nC
Reverse Recovery Fall Time	t _a			10		ns
Reverse Recovery Rise Time	t _b			7		

Notes:

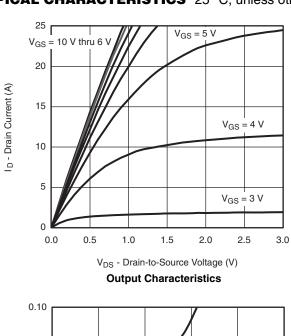
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

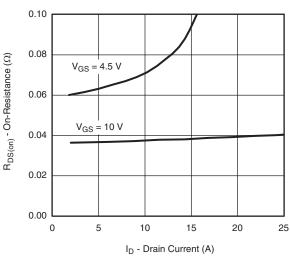
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

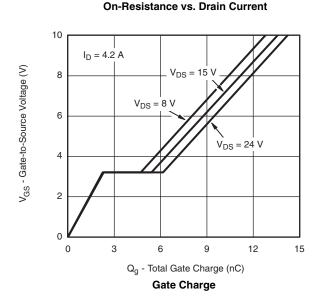


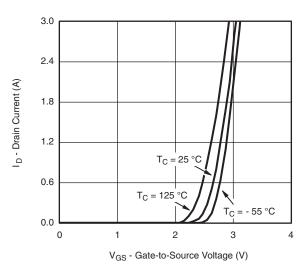


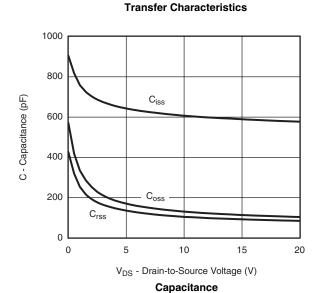
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

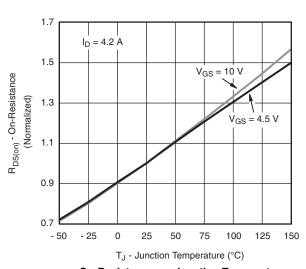










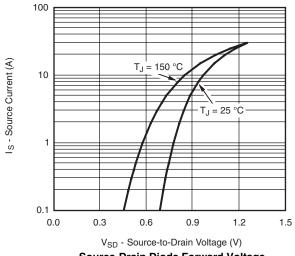


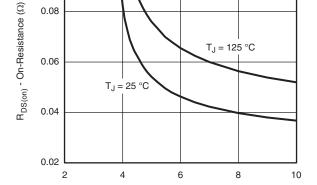
On-Resistance vs. Junction Temperature

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 $I_D = 4.2 A$

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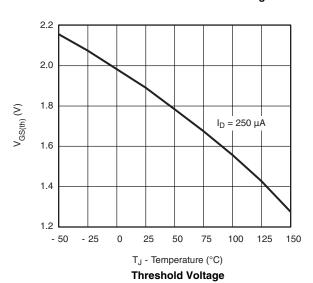


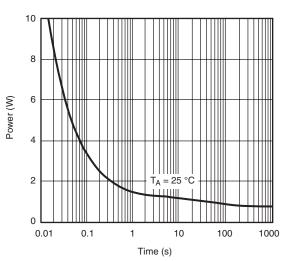


0.10

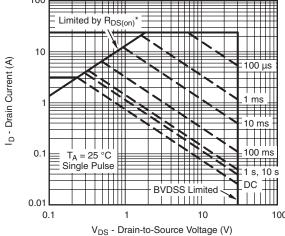
Source-Drain Diode Forward Voltage

V_{GS} - Gate-to-Source Voltage (V) On-Resistance vs. Gate-to-Source Voltage





Single Pulse Power (Junction-to-Ambient)

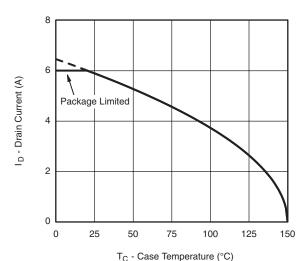


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

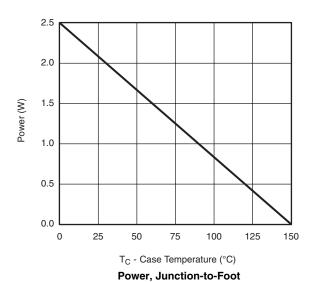


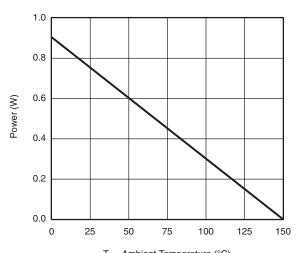
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



C - Case Temperature (*C)

Current Derating*





T_A - Ambient Temperature (°C)

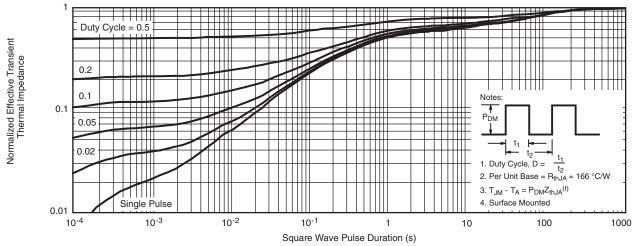
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

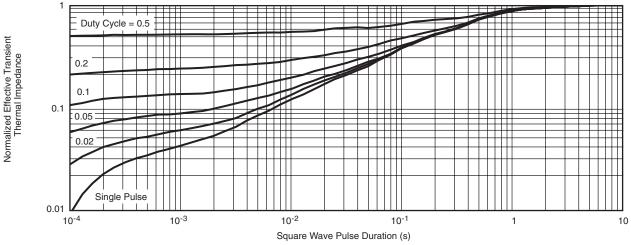
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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